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PATENT

Attorney Docket No.: SAM-0210

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Mullen

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): Chang-Whan Jung, *et al.* Examiner: Nguyen, Minh
Serial No.: 09/879,637 Group Art Unit: 2816
Filing Date: June 12, 2001
Title: FUSE CIRCUIT FOR SEMICONDUCTOR INTEGRATED CIRCUIT

CERTIFICATE OF MAILING UNDER 37 C.F.R. § 1.8

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2-20-03

Date

Vanessa Marakas

BOX NON-FEE AMENDMENT
Assistant Commissioner for Patents
Washington, DC 20231

AMENDMENT A

Sir:

The following is in response to the Office Action dated November 5, 2002 and is filed within the shortened statutory period of three months. Please amend the application as follows.

In the specification:

Please amend the abstract of the invention as follows.

(Amended) In a fuse circuit including programmable fuses in a semiconductor integrated circuit, the fuses store specific information related to the semiconductor integrated circuit, such as redundancy information, wafer lot number, die lot number, and die position on the wafer, etc. The fuse circuit utilizes a plurality of fuses for storing identical bit information. Consequently, in the case where a fuse has not been cut out correctly, the fuse circuit of the present invention can reduce programming defects, whereby defect generation rates are remarkably decreased.

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